

P-Ch 100V Fast Switching MOSFETs

General Description

The QM0007K is the highest performance trench P-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the small power switching and load switch applications.

The QM0007K meet the RoHS and Green Product requirement with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

Product Summery



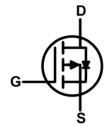
BVDSS	RDSON ID	
-100V	0.65Ω	-0.9A

Applications

- High Frequency Point-of-Load Synchronous
 Small power switching for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOT23 Pin Configuration





Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	
V_{DS}	Drain-Source Voltage	-100	V	
V_{GS}	Gate-Source Voltage	±20	V	
I _D @T _A =25℃	Continuous Drain Current, V _{GS} @ -10V ¹	-0.9	А	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ -10V ¹	-0.7	Α	
I _{DM}	Pulsed Drain Current ²	-1.8	Α	
P _D @T _A =25°C	Total Power Dissipation ³	1	W	
T _{STG}	Storage Temperature Range -55 to 150		$^{\circ}$	
T _J	Operating Junction Temperature Range -55 to 150		℃	

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
$R_{ heta JA}$	Thermal Resistance Junction-ambient ¹		125	°C/W
$R_{ heta JC}$	Thermal Resistance Junction-Case ¹		80	°C/W



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Electrical Characteristics (T_J=25 ℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} =0V , I_D =-250uA	-100			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25 $^{\circ}\mathrm{C}$, $I_D\text{=-1mA}$		-0.0624		V/°C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-0.8A		0.52	0.65	Ω
		V_{GS} =-4.5V , I_D =-0.4A		0.56	0.7	
$V_{GS(th)}$	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.0	-1.5	-2.5	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient			4.5		mV/℃
	Drain-Source Leakage Current	V_{DS} =-80V , V_{GS} =0V , T_J =25 $^{\circ}$ C			10	uA
I _{DSS}		V_{DS} =-80V , V_{GS} =0V , T_J =55 $^{\circ}$ C			100	uA
I _{GSS}	Gate-Source Leakage Current	V_{GS} = $\pm 20 V$, V_{DS} = $0 V$			±100	nA
gfs	Forward Transconductance	V_{DS} =-5V , I_D =-0.8A		3		S
R_g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		16	32	Ω
Q_g	Total Gate Charge (-4.5V)	V _{DS} =-15V , V _{GS} =-4.5V , I _D =-0.5A		4.5		
Q_gs	Gate-Source Charge			1.14		nC
Q_gd	Gate-Drain Charge			1.5		
T _{d(on)}	Turn-On Delay Time			13.6		
T _r	Rise Time	V_{DD} =-50V , V_{GS} =-10V , R_{G} =3.3 Ω		6.8		no
T _{d(off)}	Turn-Off Delay Time	I _D =-0.5A		34		ns
T _f	Fall Time			3		
Ciss	Input Capacitance	V _{DS} =-15V , V _{GS} =0V , f=1MHz		553		
C _{oss}	Output Capacitance			29		pF
C _{rss}	Reverse Transfer Capacitance			20		

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,4}	V _G =V _D =0V , Force Current			-0.9	Α
I _{SM}	Pulsed Source Current ^{2,4}	VG-VD-UV , FOICE Cullent			-1.8	Α
V_{SD}	Diode Forward Voltage ²	V_{GS} =0V , I_{S} =-1A , T_{J} =25 $^{\circ}$ C			-1.2	V

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2% 3.The power dissipation is limited by 150 $^{\circ}$ C junction temperature
- 4.The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics

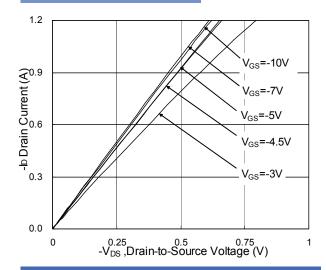


Fig.1 Typical Output Characteristics

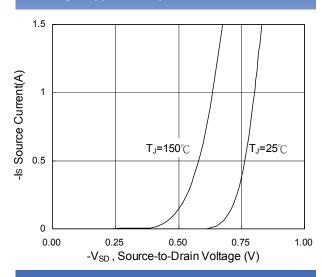


Fig.3 Forward Characteristics Of Reverse

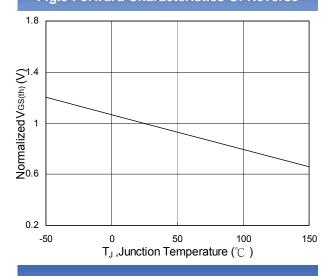


Fig.5 Normalized V_{GS(th)} vs. T_J

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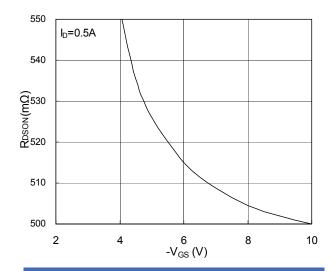


Fig.2 On-Resistance vs. Gate-Source

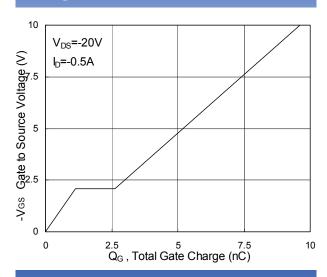


Fig.4 Gate-Charge Characteristics

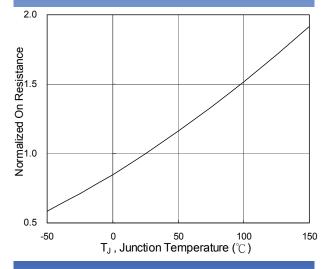
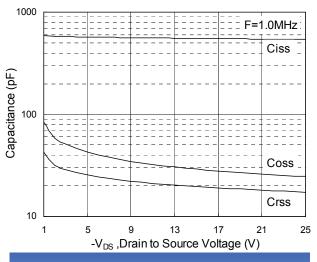


Fig.6 Normalized R_{DSON} vs. T_J



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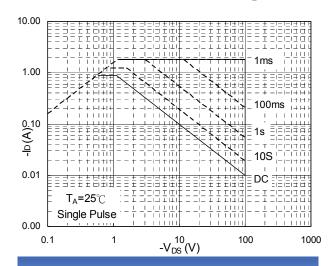


Fig.7 Capacitance

Fig.8 Safe Operating Area

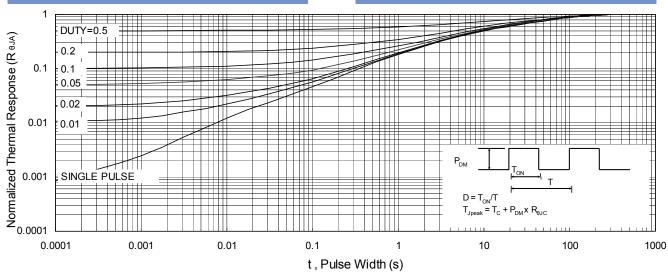
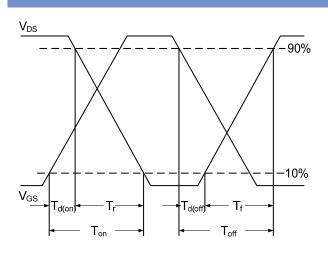


Fig.9 Normalized Maximum Transient Thermal Impedance



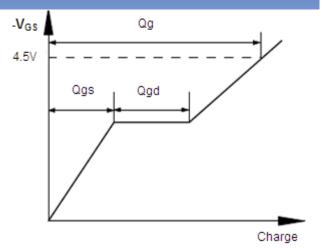


Fig.10 Switching Time Waveform

Fig.11 Gate Charge Waveform